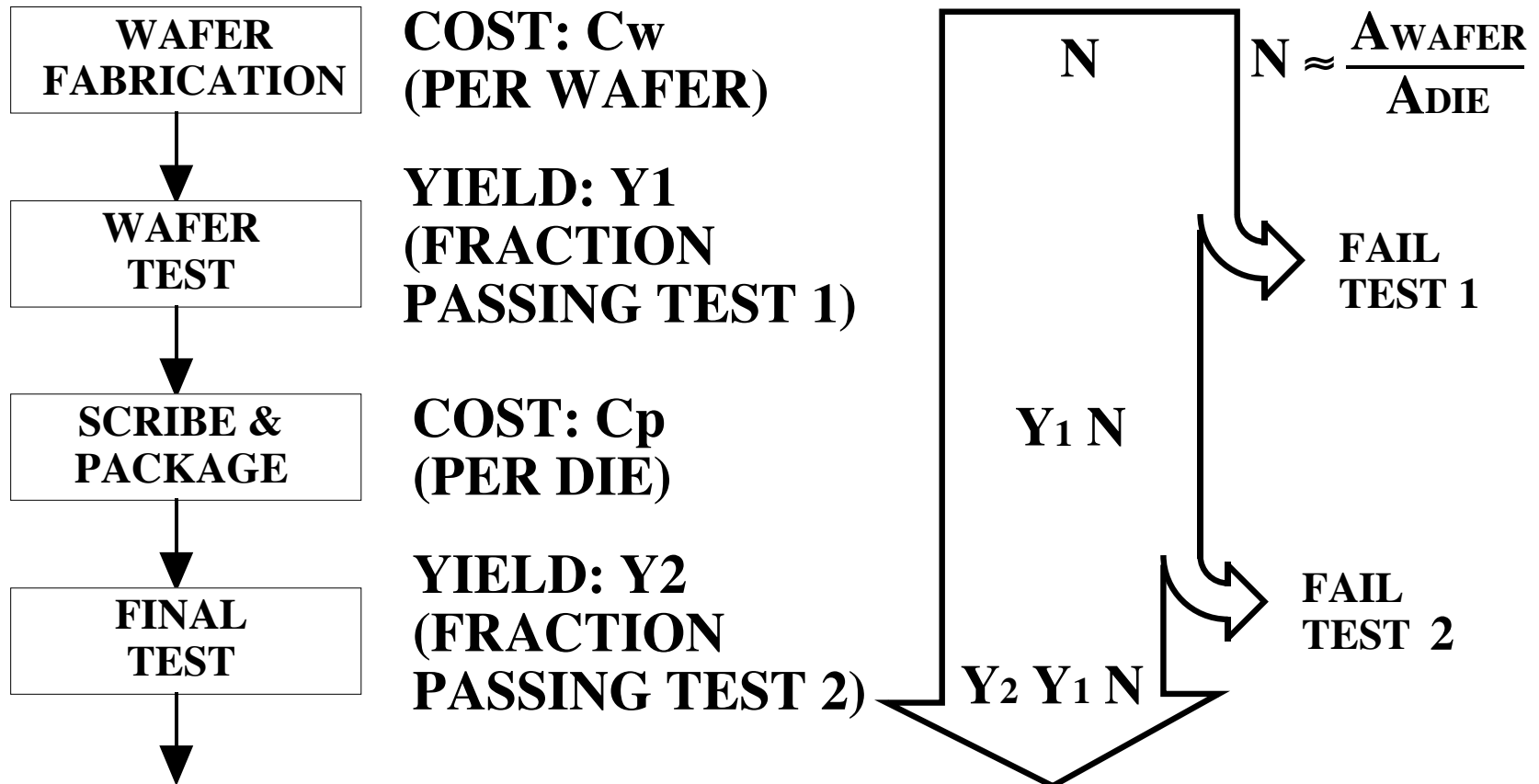


Overview

- **IC Fabrication: Silicon Run video**
- **Process Flow**
- **Economic Issues**

Process Flow

N: Gross die per wafer



$Y_2 Y_1 N = N_G$: Good die per wafer

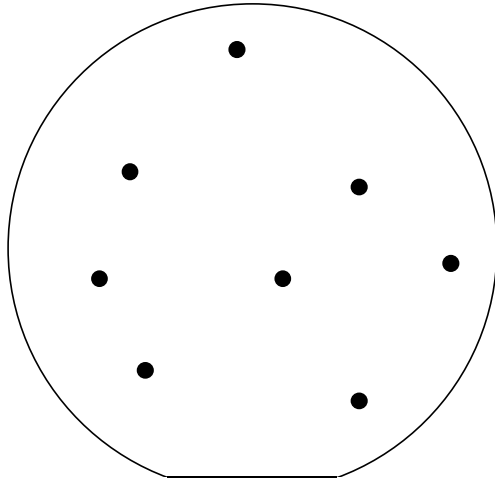
Cost per Die

- **Total Cost** $C_W + Y_1 N C_P$
- **Total number of good die** $Y_1 Y_2 N$
- **Cost per good die** $\frac{C_W + Y_1 N C_P}{Y_1 Y_2 N} = \frac{C_W}{\underbrace{Y_1 Y_2 N}_{\substack{\text{WAFER} \\ \text{FAB}}}} + \frac{C_P}{\underbrace{Y_2}_{\text{PACKAGE}}}$

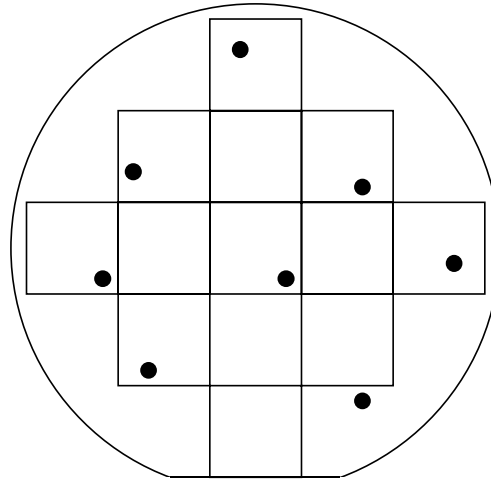
Benefits of Smaller Chip Area

- **More die per wafer (higher N)**
- **Higher Yield**

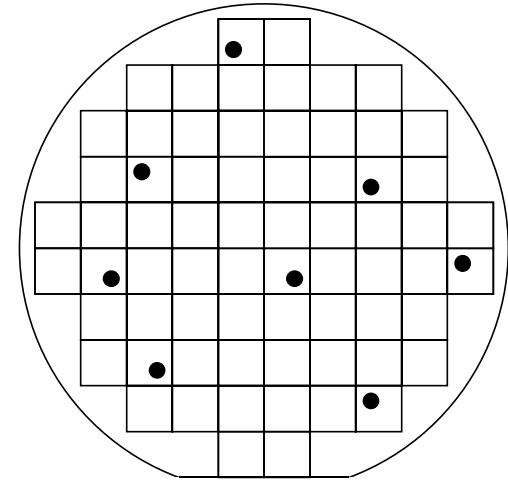
Smaller Die Size: Higher Yield



**POINT DEFECTS
RANDOMLY DISTRIBUTED
OVER WAFER**

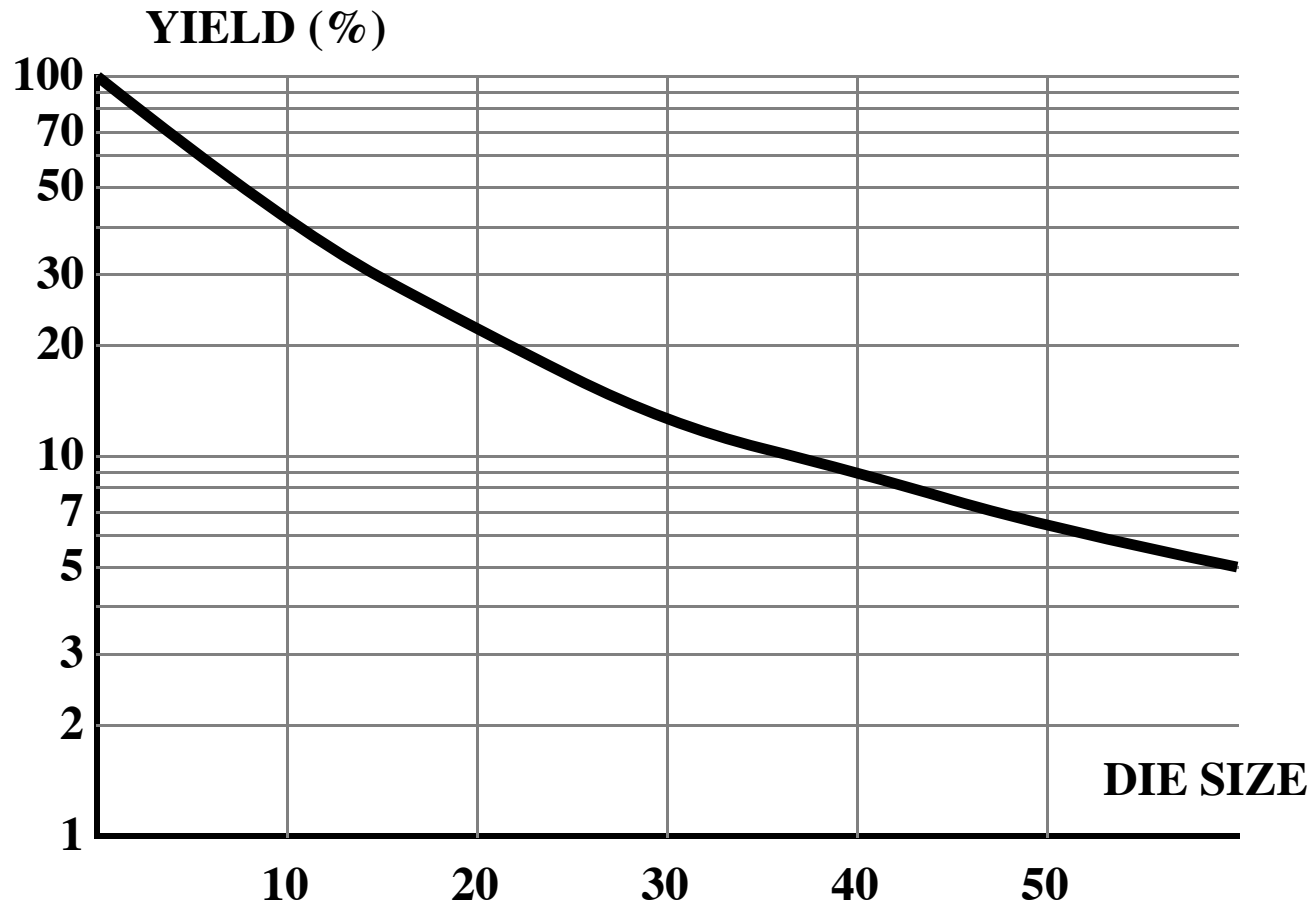


**N = 13 die
6 good
 $Y = 6/13 = 46\%$**



**N = 68
60 good
 $Y = 60/68 = 88\%$**

Example: Yield vs. die size



Example

- **Process:**
 - **20cm diameter wafer**
 - **Wafer cost: $C_W = \$4000$ per wafer**
 - **Package cost: $C_P = \$1.70$ per package**
 - **Final test yield: $Y_2 = 0.95$**
- **$A_{DIE} = 40\text{mm}^2$**

Die per wafer $A_{DIE}=40\text{mm}^2$

- **Wafer area**

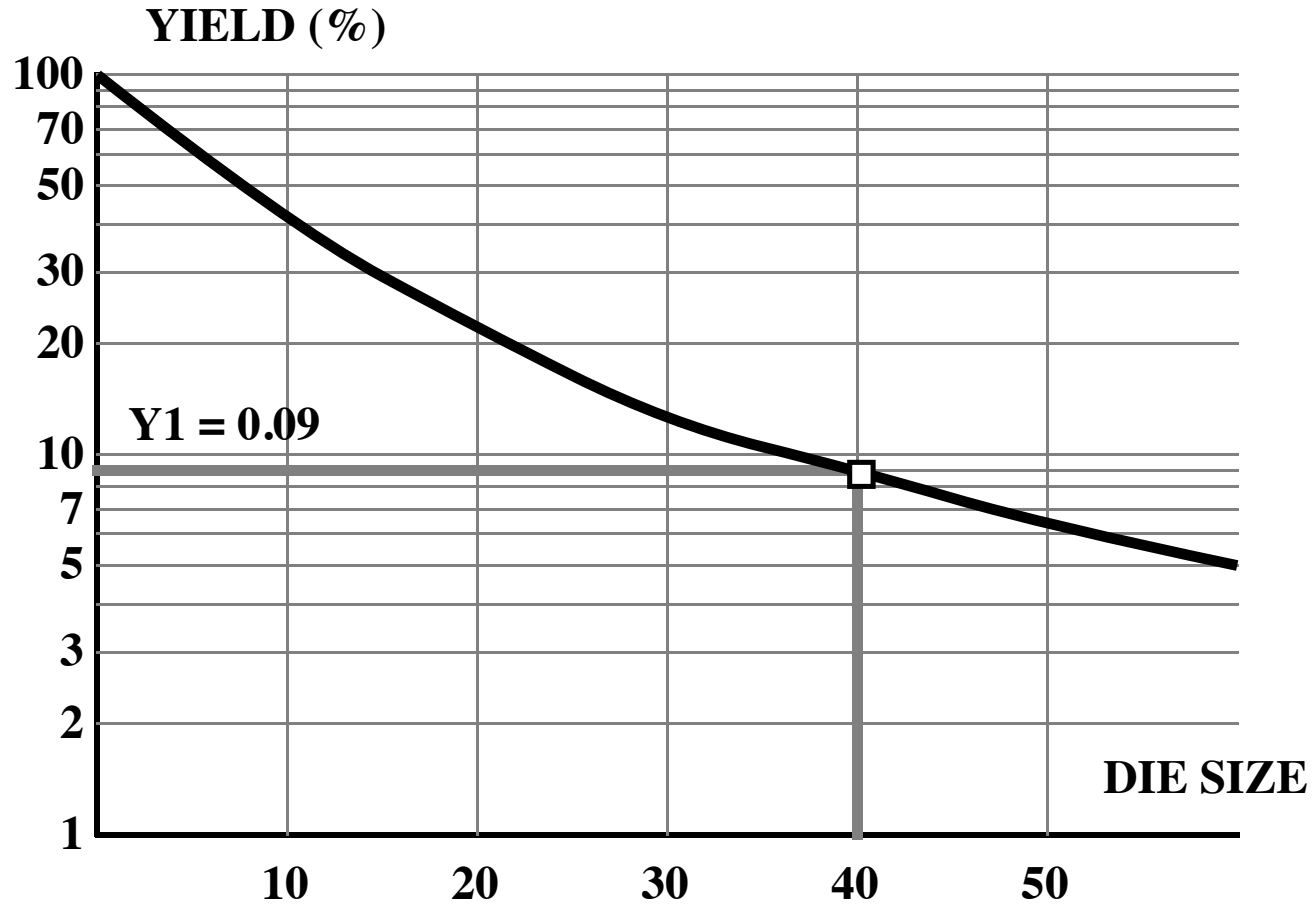
Wafer diameter = 20cm = 200mm $\Rightarrow r=100\text{mm}$

$$A_{WAFER} = \pi r^2 = \pi(100\text{mm})^2 = 3.14E + 04\text{mm}^2$$

- **Gross die per wafer**

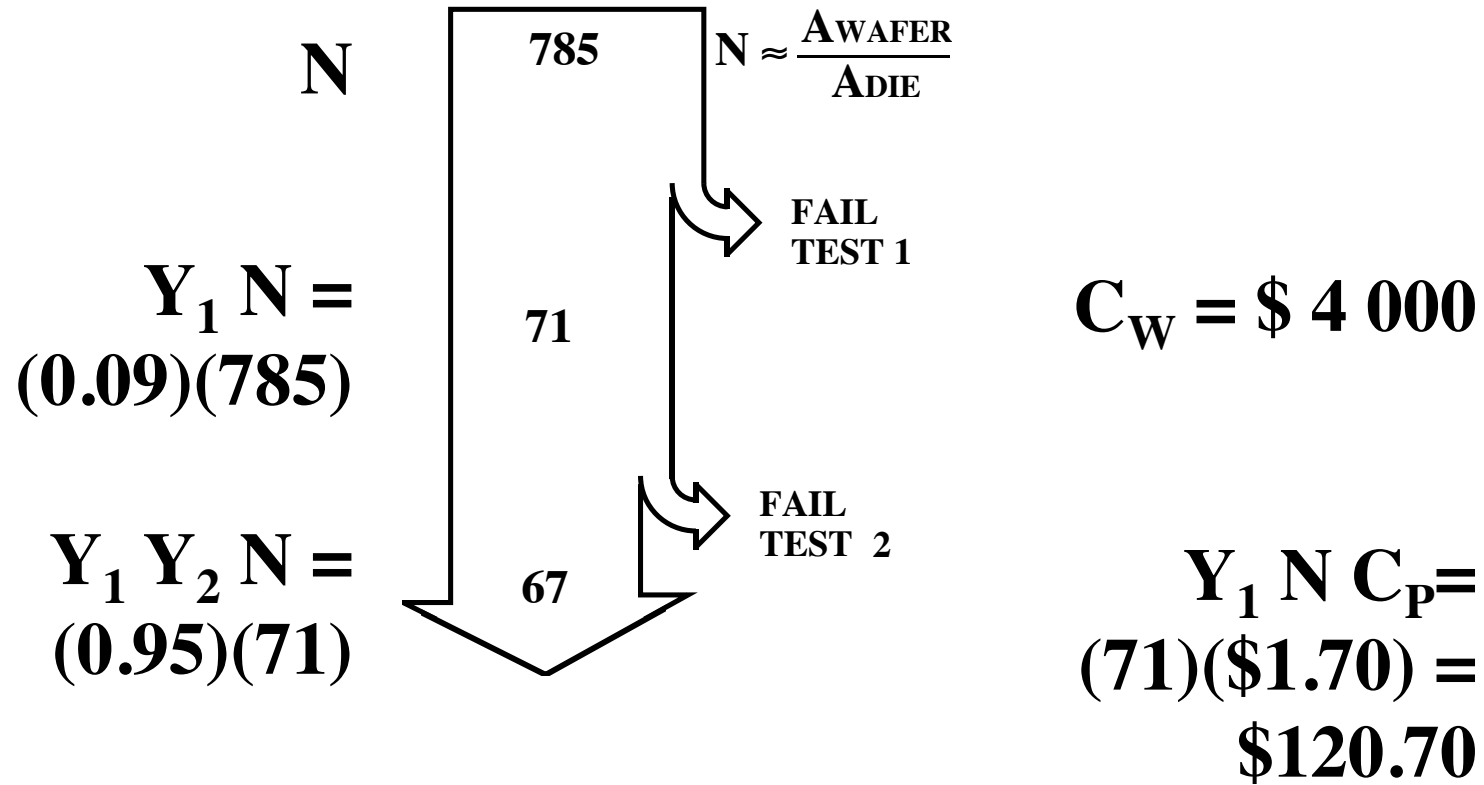
$$N = \frac{A_{WAFER}}{A_{DIE}} = \frac{3.14E + 04\text{mm}^2}{40\text{mm}^2} = 785$$

Yield $A_{DIE}=40\text{mm}^2$



Process flow $A_{DIE}=40\text{mm}^2$

COST



Cost per die $A_{\text{DIE}}=40\text{mm}^2$

- **Total cost: \$ 4 120 . 70**
- **Good die: 67**
- **Cost per good die: $C = \frac{\$4120.70}{67} = \61.50**

- **Reduce die area by 4X to 10 mm²**
 - **Difficult (Big = Easy)**
 - **Example: computer science**
 - **Worth the effort? Cost impact?**

Die per wafer $A_{DIE}=10\text{mm}^2$

- **Wafer area**

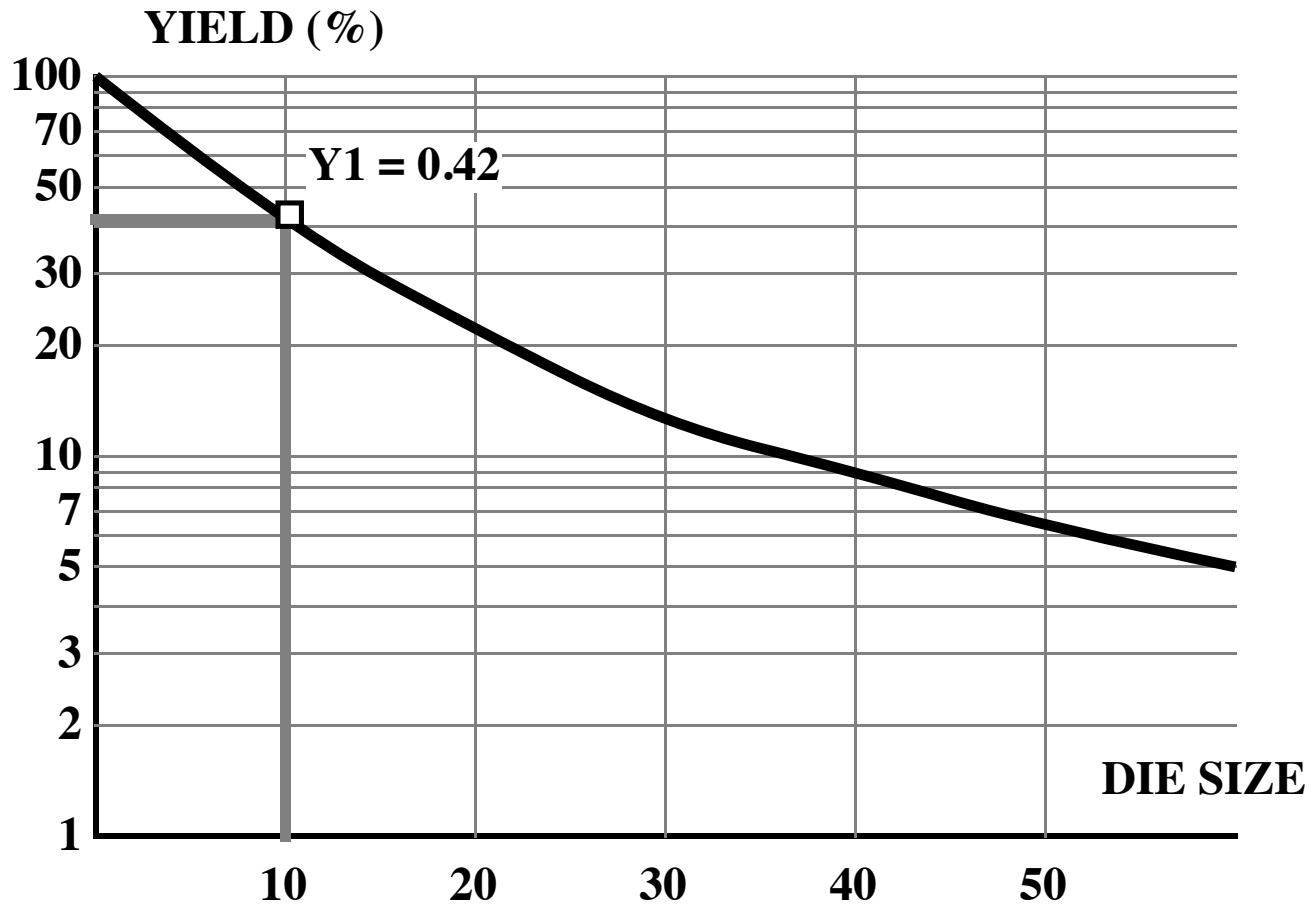
Wafer diameter = 20cm = 200mm $\Rightarrow r=100\text{mm}$

$$A_{WAFER} = \pi r^2 = \pi(100\text{mm})^2 = 3.14E + 04\text{mm}^2$$

- **Gross die per wafer**

$$N = \frac{A_{WAFER}}{A_{DIE}} = \frac{3.14E + 04\text{mm}^2}{10\text{mm}^2} = 3140$$

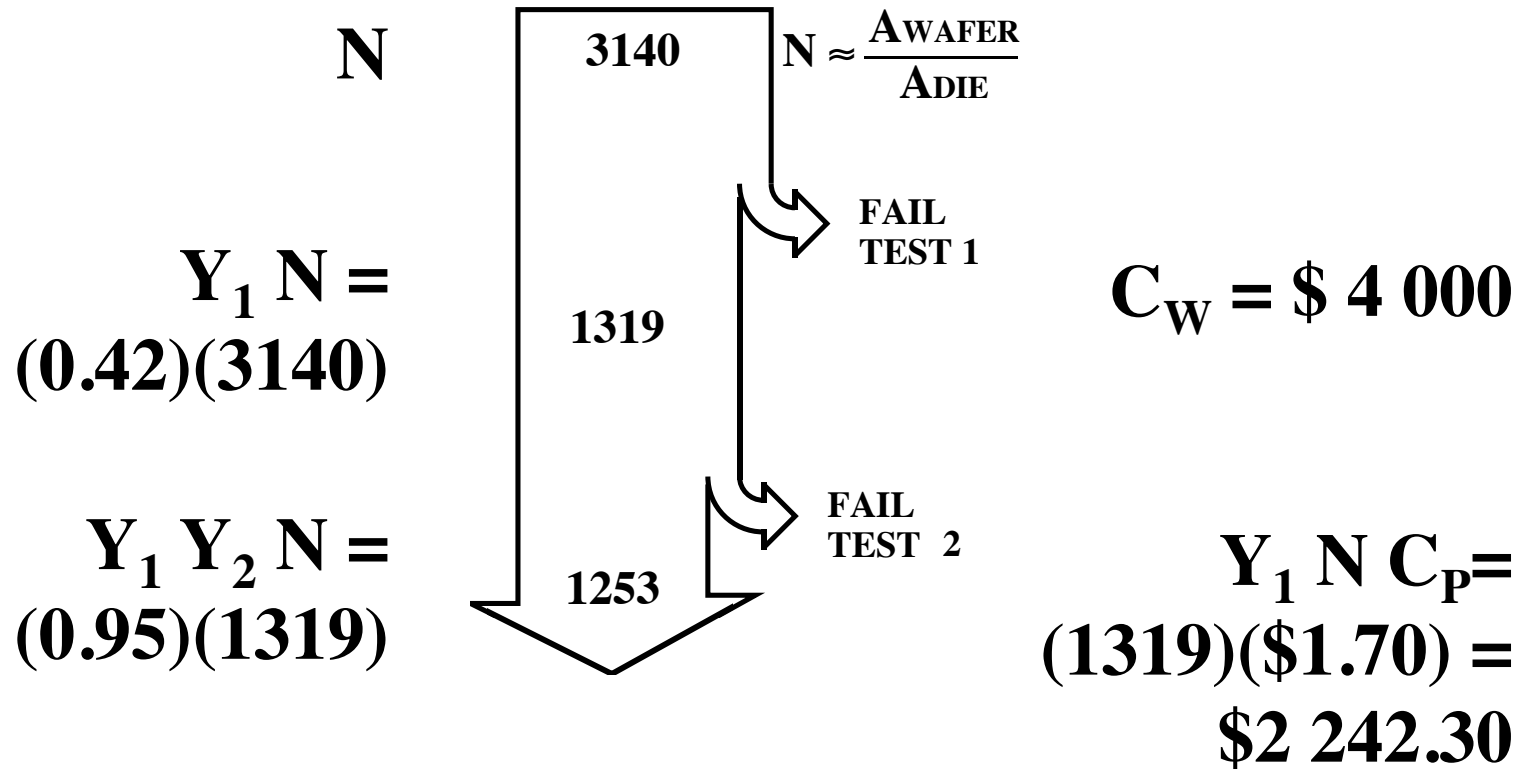
Yield $A_{DIE}=10\text{mm}^2$



- Compare to yield $Y_1=0.09$ for $A_{DIE} = 40\text{mm}^2$

Process flow $A_{DIE}=10\text{mm}^2$

COST



Cost per die $A_{\text{DIE}}=10\text{mm}^2$

- Total cost: \$ 6 242 . 30
- Good die: 1253
- Cost per good die: $C = \frac{\$6242.30}{1253} = \4.98
- Compare to $C = \$61.50$ for $A_{\text{DIE}}=40\text{mm}^2$
- Reducing die area by 4X
reduces cost by better than 10X

Definitely worth the effort!

Summary

- **IC Fabrication Process**
- **Process Flow**
- **Costs:**
 - **Wafer cost (fixed per wafer)**
 - **Package cost (per die)**
- **Key: minimize die area**
- **Implication for circuit design: Area of devices more important than number of devices**